

DS26C31T/DS26C31M CMOS Quad TRI-STATE® Differential Line Driver

General Description

The DS26C31 is a quad differential line driver designed for digital data transmission over balanced lines. The DS26C31T meets all the requirements of EIA standard RS-422 while retaining the low power characteristics of CMOS. The DS26C31M is compatible with EIA standard RS-422; however, one exception in test methodology is taken (Note 8). This enables the construction of serial and terminal interfaces while maintaining minimal power consumption.

The DS26C31 accepts TTL or CMOS input levels and translates these to RS-422 output levels. This part uses special output circuitry that enables the drivers to power down without loading down the bus. This device has enable and disable circuitry common to all four drivers. The DS26C31 is pin compatible to the AM26LS31 and the DS26LS31.

All inputs are protected against damage due to electrostatic discharge by diodes to $\rm V_{\rm CC}$ and ground.

Features

- TTL input compatible
- Typical propagation delays: 6 ns
- Typical output skew: 0.5 ns
- Outputs will not load line when V_{CC} = 0V
- DS26C31T meets the requirements of EIA standard RS-422
- Operation from single 5V supply
- TRI-STATE outputs for connection to system buses
- Low quiescent current
- Available in surface mount
- Mil-Std-883C compliant

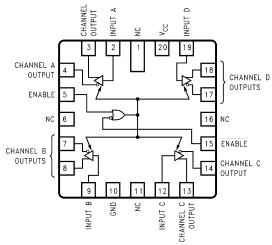
Connection Diagrams

Dual-In-Line Package INPUT A INPUT D **CHANNEL A** OUTPUTS CHANNEL D 13 OUTPUTS **ENABLE** 12 ENABLE CHANNEL B OUTPUTS CHANNEL C OUTPUTS INPUT B GND:

Top View
Order Number DS26C31TM or DS26C31TN
See NS Package Number M16A or N16E
For Complete Military Product Specifications,
refer to the appropriate SMD or MDS.
Order Number DS26C31ME/883, DS26C31MJ/883
or DS26C31MW/883

See NS Package Number E20A, J16A or W16A

20-Lead Ceramic Leadless Chip Carrier (E)



00857412

Truth Table

ENABLE	ENABLE	Input	Non-Inverting	Inverting
			Output	Output
L	Н	Х	Z	Z
All o	ther	L	L	Н
combina	ations of	Н	Н	L
enable inputs				

L = Low logic state

X = Irrelevant

H = High logic state

Z = TRI-STATE (high impedance)

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Absolute Maximum Ratings (Notes 1,

2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

per pin (I_{CC}) ± 150 mA Storage Temperature Range (T_{STG}) -65° C to $+150^{\circ}$ C

Max. Power Dissipation (P_D) @25°C (Note 3)

Ceramic "J" Pkg. 2419 mW Plastic "N" Pkg. 1736 mW

SOIC "M" Pkg. 1226 mW Ceramic "W" Pkg. 1182 mW Ceramic "E" Pkg. 2134 mW Lead Temperature (T_L) (Soldering, 4 sec.) 260°C

This device does not meet 2000V ESD Rating. (Note 13)

Operating Conditions

	Min	Max	Units
Supply Voltage (V _{CC})	4.50	5.50	V
DC Input or Output Voltage			
(V_{IN}, V_{OUT})	0	V_{CC}	V
Operating Temperature Range (T _A)			
DS26C31T	-40	+85	°C
DS26C31M	-55	+125	°C
Input Rise or Fall Times (t _r , t _f)		500	ns

DC Electrical Characteristics

 V_{CC} = 5V ± 10% (unless otherwise specified) (Note 4)

Symbol	Parameter		Conditions	Min	Тур	Max	Units
V _{IH}	High Level Input Voltage			2.0			V
V _{IL}	Low Level Input Voltage					0.8	V
V _{OH}	High Level Output Voltage	$V_{IN} = V_{IH} \text{ or } V_{I}$	L,	2.5	3.4		V
		$I_{OUT} = -20 \text{ mA}$	1				
V _{OL}	Low Level Output	$V_{IN} = V_{IH} \text{ or } V_{I}$	L,		0.3	0.5	V
	Voltage	$I_{OUT} = 20 \text{ mA}$					
V _T	Differential Output	$R_L = 100\Omega$		2.0	3.1		V
	Voltage	(Note 5)					
$ V_T - \overline{V_T} $	Difference In	$R_L = 100\Omega$				0.4	V
	Differential Output	(Note 5)					
V _{OS}	Common Mode	$R_L = 100\Omega$			1.8	3.0	V
	Output Voltage	(Note 5)					
IV _{OS} - V _{OS} I	Difference In	$R_L = 100\Omega$				0.4	V
	Common Mode Output	(Note 5)					
I _{IN}	Input Current	V _{IN} = V _{CC} , GN			±1.0	μΑ	
I _{cc}	Quiescent Supply	DS26C31T	$V_{IN} = V_{CC}$ or GND		200	500	μΑ
	Current (Note 6)	$I_{OUT} = 0 \mu A$	$V_{IN} = 2.4V \text{ or } 0.5V$		0.8	2.0	mA
			(Note 6)				
		DS26C31M	V _{IN} = V _{CC} or GND		200	500	μΑ
		$I_{OUT} = 0 \mu A$	$V_{IN} = 2.4V \text{ or } 0.5V$		0.8	2.1	mA
			(Note 6)				
l _{oz}	TRI-STATE Output	V _{OUT} = V _{CC} or	GND				
	Leakage Current	ENABLE = V _{IL}			±0.5	±5.0	μΑ
		ENABLE = V _{IH}					
I _{sc}	Output Short	$V_{IN} = V_{CC}$ or G	ND	-30		-150	mA
	Circuit Current	(Notes 5, 7)					
I _{OFF}	Output Leakage Current	DS26C31T	V _{OUT} = 6V			100	μΑ
	Power Off (Note 5)	$V_{CC} = 0V$	$V_{OUT} = -0.25V$			-100	μΑ
		DS26C31M	V _{OUT} = 6V			100	μΑ
		$V_{CC} = 0V$	V _{OUT} = 0V			-100	μΑ
			(Note 8)				

DC Electrical Characteristics (Continued)

Note 1: Absolute Maximum Ratings are those values beyond which the safety of the device cannot be guaranteed. They are not meant to imply that the device should be operated at these limits. The table of "Electrical Characteristics" provide conditions for actual device operation.

Note 2: Unless otherwise specified, all voltages are referenced to ground. All currents into device pins are positive, all currents out of device pins are negative.

Note 3: Ratings apply to ambient temperature at 25°C. Above this temperature derate N package at 13.89 mW/°C, J package 16.13 mW/°C, M package 9.80 mW/°C, E package 12.20 mW/°C, and W package 6.75 mW/°C.

Note 4: Unless otherwise specified, min/max limits apply across the recommended operating temperature range. All typicals are given for $V_{CC} = 5V$ and $T_A = 25^{\circ}C$.

Note 5: See EIA Specification RS-422 for exact test conditions.

Note 6: Measured per input. All other inputs at $V_{\mbox{\footnotesize{CC}}}$ or GND.

Note 7: This is the current sourced when a high output is shorted to ground. Only one output at a time should be shorted.

Note 8: The DS26C31M (-55°C to +125°C) is tested with V_{OUT} between +6V and 0V while RS-422A condition is +6V and -0.25V.

Switching Characteristics

 V_{CC} = 5V ±10%, $t_r \le 6$ ns, $t_f \le 6$ ns (Figures 1, 2, 3, 4) (Note 4)

Symbol	Parameter	Conditions	Min	Тур	M	Units	
					DS26C31T	CS26C31M	1
t _{PLH} , t _{PHL}	Propagation Delays	S1 Open	2	6	11	14	ns
	Input to Output						
Skew	(Note 9)	S1 Open		0.5	2.0	3.0	ns
t _{TLH} , t _{THL}	Differential Output Rise	S1 Open		6	10	14	ns
	And Fall Times						
t _{PZH}	Output Enable Time	S1 Closed		11	19	22	ns
t _{PZL}	Output Enable Time	S1 Closed		13	21	28	ns
t _{PHZ}	Output Disable Time	S1 Closed		5	9	12	ns
	(Note 10)						
t _{PLZ}	Output Disable Time	S1 Closed		7	11	14	ns
	(Note 10)						
C _{PD}	Power Dissipation			50			pF
	Capacitance (Note 11)						
C _{IN}	Input Capacitance			6			pF

Note 9: Skew is defined as the difference in propagation delays between complementary outputs at the 50% point.

Note 10: Output disable time is the delay from ENABLE or ENABLE being switched to the output transistors turning off. The actual disable times are less than indicated due to the delay added by the RC time constant of the load.

Note 11: C_{PD} determines the no load dynamic power consumption, P_D = C_{PD} V_{CC}2 f + I_{CC} V_{CC}, and the no load dynamic current consumption, I_S = C_{PD} V_{CC} f + I_{CC}.

Comparison Table of Switching Characteristics into "LS-Type" Load

 $V_{CC} = 5V$, $T_A = 25^{\circ}C$, $t_r \le 6$ ns, $t_f \le 6$ ns (Figures 2, 4, 5, 6) (Note 12)

Symbol	Parameter	Conditions	DS26	C31T	DS26	LS31C	Units
			Тур	Max	Тур	Max	
t _{PLH} , t _{PHL}	Propagation Delays	C _L = 30 pF					
	Input to Output	S1 Closed	6	8	10	15	ns
		S2 Closed					
Skew	(Note 9)	C _L = 30 pF					
		S1 Closed	0.5	1.0	2.0	6.0	ns
		S2 Closed					
t _{THL} , t _{TLH}	Differential Output Rise	C _L = 30 pF					
	and Fall Times	S1 Closed	4	6			ns
		S2 Closed					
t _{PLZ}	Output Disable Time	C _L = 10 pF					
	(Note 10)	S1 Closed	6	9	15	35	ns
		S2 Open					

Comparison Table of Switching Characteristics into "LS-Type"

Load (Continued)

 $V_{CC} = 5V$, $T_A = 25^{\circ}C$, $t_r \le 6$ ns, $t_f \le 6$ ns (Figures 2, 4, 5, 6) (Note 12)

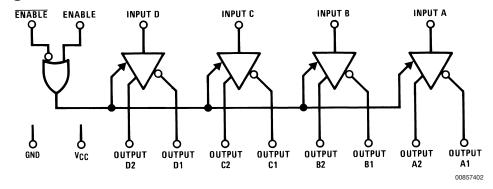
Symbol	Parameter	Conditions	DS26	C31T	DS26	Units	
			Тур	Max	Тур	Max	
t _{PHZ}	Output Disable Time	C _L = 10 pF					
	(Note 10)	S1 Open	4	7	15	25	ns
		S2 Closed					
t _{PZL}	Output Enable Time	C _L = 30 pF					
		S1 Closed	14	20	20	30	ns
		S2 Open					
t _{PZH}	Output Enable Time	C _L = 30 pF					
		S1 Open	11	17	20	30	ns
		S2 Closed					

Note 12: This table is provided for comparison purposes only. The values in this table for the DS26C31 reflect the performance of the device but are not tested or guaranteed.

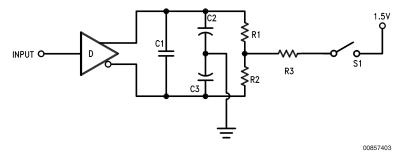
Note 13: ESD Rating:

HBM (1.5 kΩ, 100 pF) Inputs \geq 1500V Outputs \geq 1000V EIAJ (0Ω, 200 pF) \geq 350V

Logic Diagram



AC Test Circuit and Switching Time Waveforms



Note: C1 = C2 = C3 = 40 pF (Including Probe and Jig Capacitance), R1 = R2 = 50Ω , R3 = 500Ω .

FIGURE 1. AC Test Circuit

AC Test Circuit and Switching Time Waveforms (Continued)

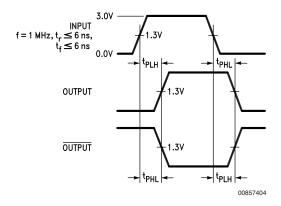


FIGURE 2. Propagation Delays

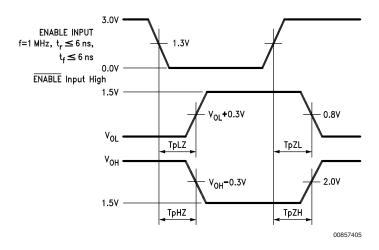
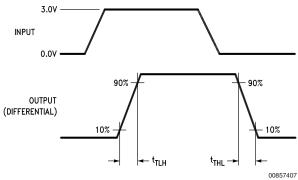


FIGURE 3. Enable and Disable Times



Input pulse; f = 1 MHz, 50%; $t_r \le 6$ ns, $t_f \le 6$ ns

FIGURE 4. Differential Rise and Fall Times

AC Test Circuit and Switching Time Waveforms (Continued)

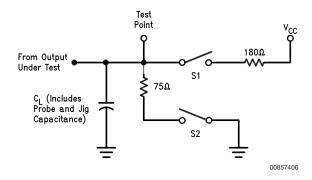


FIGURE 5. Load AC Test Circuit for "LS-Type" Load

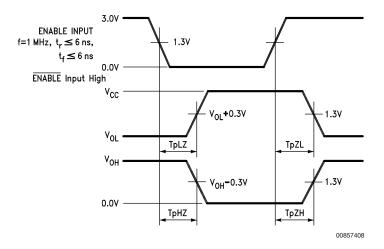
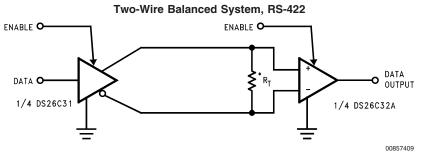


FIGURE 6. Enable and Disable Times for "LS-Type" Load

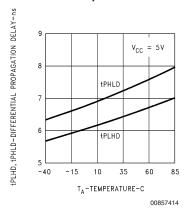
Typical Applications



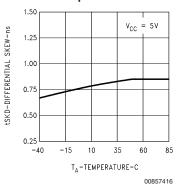
*R_T is optional although highly recommended to reduce reflection.

Typical Performance Characteristics

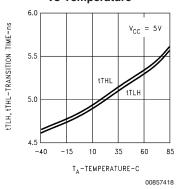
Differential Propagation Delay vs Temperature



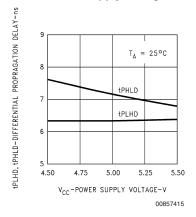
Differential Skew vs Temperature



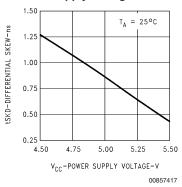
Differential Transition Time vs Temperature



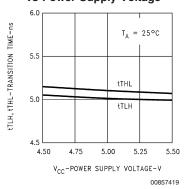
Differential Propagation Delay vs Power Supply Voltage



Differential Skew vs Power Supply Voltage

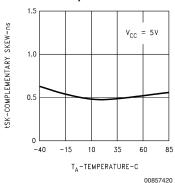


Differential Transition Time vs Power Supply Voltage

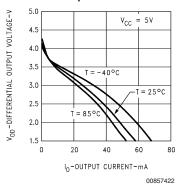


Typical Performance Characteristics (Continued)

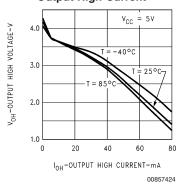
Complementary Skew vs Temperature



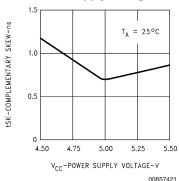
Differential Output Voltage vs Output Current



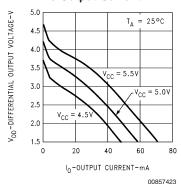
Output High Voltage vs Output High Current



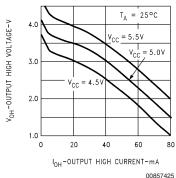
Complementary Skew vs Power Supply Voltage



Differential Output Voltage vs Output Current

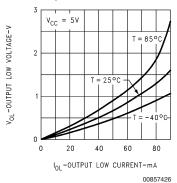


Output High Voltage vs Output High Current

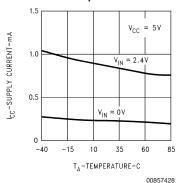


Typical Performance Characteristics (Continued)

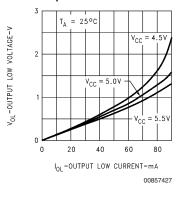
Output Low Voltage vs Output Low Current



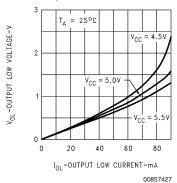
Supply Current vs Temperature



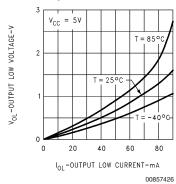
Output Low Voltage vs Output Low Current



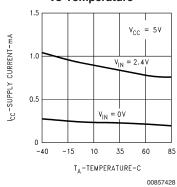
Output Low Voltage vs Output Low Current



Output Low Voltage vs Output Low Current

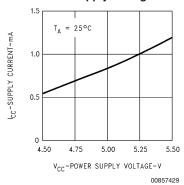


Supply Current vs Temperature

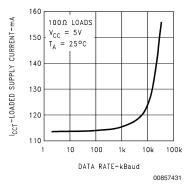


Typical Performance Characteristics (Continued)

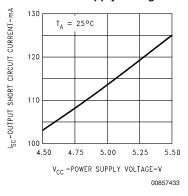
Supply Current vs Power Supply Voltage



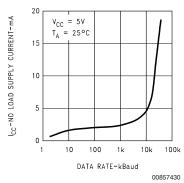
Loaded Supply Current vs Data Rate



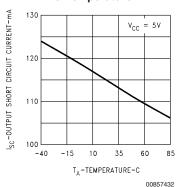
Output Short Circuit Current vs Power Supply Voltage



No Load Supply Current vs Data Rate

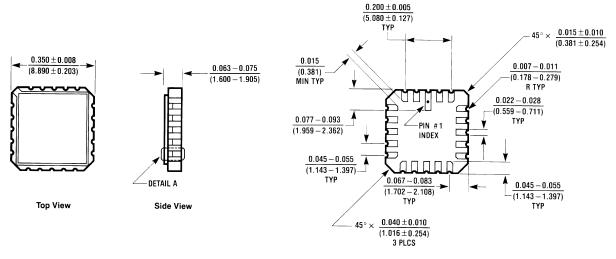


Output Short Circuit Current vs Temperature

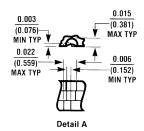


Physical Dimensions inches (millimeters)

unless otherwise noted

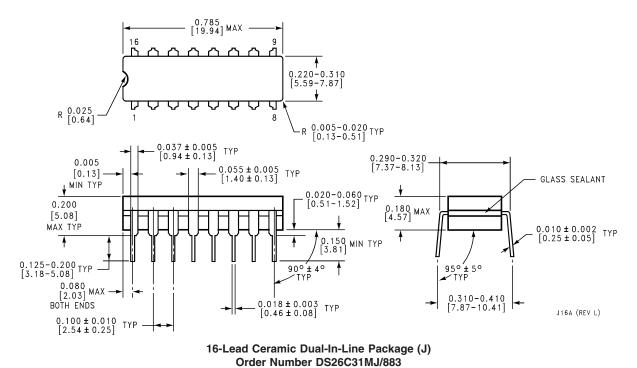


Bottom View



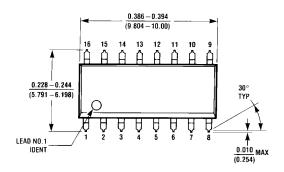
E20A (REV D)

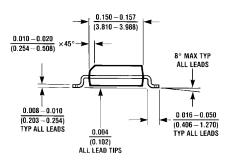
20-Lead Ceramic Leadless Chip Carrier (E) Order Number DS26C31ME/883 NS Package Number E20A

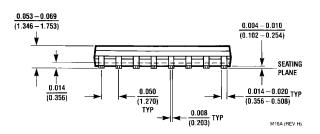


NS Package Number J16A

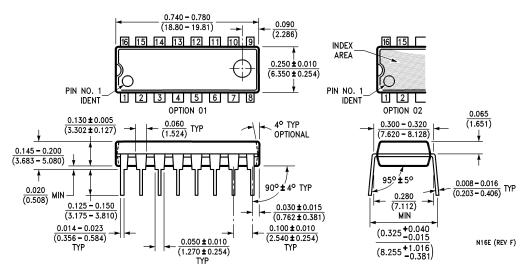
Physical Dimensions inches (millimeters) unless otherwise noted (Continued)





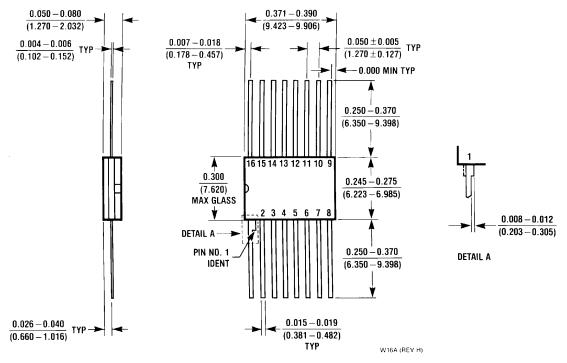


Molded Package Small Outline (M) Order Number DS26C31TM NS Package Number M16A



16-Lead Molded Dual-In-Line Package (N) Order Number DS26C31TN NS Package Number N16E

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



16-Lead Ceramic Flatpak Package (W) Order Number DS26C31MW/883 NS Package Number W16A

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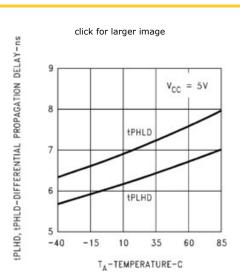


DS26C31M - CMOS Quad TRI STATE Differential Line Drivers

Datasheet	Packaging	Samples & Pricing	Reliability	Knowledge Base	
Features		Typical Application		Connection Diagram	
• TTL input compatible • Typical propagation delays • Typical output skew: 0.5 ns • Outputs will not load line w • DS26C31T meets the requ • Operation from single 5V s • TRI-STATE outputs for con • Low quiescent current • Available in surface mount • Mil-Std-883C compliant	then $V_{CC} = 0V$ irements of EIA standard RS-422 upply	Click DATA O 1/4 0526C31 Parametric Table expa	for larger image EMABLE O DATA OUTPUT 1/4 DS26C32A	Click for larger ima	16 5V 15 INPUT D 14 CHANNEL D 0017PUTS 12 ENABLE 11 CHANNEL C
General Description		Drivers Receivers	4	INPUT B	9 INPUT C
The DS26C31 is a quad diffe	erential line driver designed for digital data	SupplyVoltage Process Temperature Min	5 Volt CMOS -55 deg C		

Typical Performance

Temperature Max



-55 deg C

125 deg C

Datasheet

RoHS Compliance Information	Size in Kbytes	Date	POF
DS26C31T/DS26C31M CMOS Quad TRI-STATE® Differential Line Driver	453 Kbytes	22-Sep-04	Download
DS26C31M Mil-Aero Datasheet MNDS26C31M-X	333 Kbytes		Download

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Package Availability, Models, Samples & Pricing

	Package			Factory Lead Time			Samples &	Budgetary Pricing		Std	Package														
Part Number	Туре	Pins	Spec.	MSL Rating	Peak Reflow	RoHS Report	CAD Symbols	Weeks	Qty	Models	Electronic Orders	Qty	\$US each	Pack Size											
5962-9163901M2A	LCC	20 Rol-		RoHS	Download	Full production		N/A		50+	\$22.10	rail of	NS ZSSXXYYA DS26C31ME/												
(DS26C31ME/883)		20				поно		500	N/A	Buy Now	30+	φ22.10	50	883 Q 5962- 9163901M2A											
5962-9163901MEA	CERDIP	16				RoHS	Download	Full product	ion	N/A		50+	\$11.60	rail	NSZSSXXYYA DS26C31MJ/883 Q										
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Obsolete Versions

Obsolete Part	Alternate Part or Supplier	Source	Last Time Buy Date
DS26C31MJ-MLS	DS26C31MJ/883	NATIONAL SEMICONDUCTOR	09/08/98
DS26C31MW-MLS	DS26C31MW/883	NATIONAL SEMICONDUCTOR	09/08/98
DS26C31MWG/883	DS16F95W/883	NSCNE	12/03/2008

General Description

The DS26C31 is a quad differential line driver designed for digital data transmission over balanced lines. The DS26C31T meets all the requirements of EIA standard RS-422 while retaining the low power characteristics of CMOS. The DS26C31M is compatible with EIA standard RS-422; however, one exception in test methodology is taken. This enables the construction of serial and terminal interfaces while maintaining minimal power consumption.

The DS26C31 accepts TTL or CMOS input levels and translates these to RS-422 output levels. This part uses special output circuitry that enables the drivers to power down without loading down the bus. This device has enable and disable circuitry common to all four drivers. The DS26C31 is pin compatible to the AM26LS31 and the DS26LS31.

All inputs are protected against damage due to electrostatic discharge by diodes to $V_{\rm cc}$ and ground.

Reliability Metrics

Part Number	Process	EFR Reject	EFR Sample Size	PPM *	LTA Rejects	LTA Device Hours	FITS	MTTF (Hours)
DS26C31ME/883	CS200*	0	9850	0	0	3375000	2	957665465
DS26C31MJ/883	CS200*	0	9850	0	0	3375000	2	957665465
DS26C31MW/883	CS200*	0	9850	0	0	3375000	2	957665465

Note: The Early Failure Rates were calculated as point estimates. The Long Term Failure Rates were calculated at 60% confidence using the Arrhenius equation at 0.7eV activation energy and derating the assumed stress temperature of 150 $^{\circ}$ C to an application temperature of 55 $^{\circ}$ C.

For more information on Reliability Metrics, please click here.

[Information as of 23-Mar-2009]

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